

Search Notes

Application/Control No.

10/641,302

Applicant(s)/Patent under
Reexamination

HWANG, IN TAE

Examiner

Terence Moore

Art Unit

2609

SEARCHED

Class	Subclass	Date	Examiner
370	345	3/20/2007	TM

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IDM_TDB (see attached search strategy)	3/20/2007	TM
Inventor name and Assignee search in PALM ExPO and EAST	3/20/2007	TM
EPO Database (http://ep.espacenet.com)	3/20/2007	TM
KIPO Database (http://www.kipo.go.kr/kpo/eng/about_kipo/kpion.jsp)	3/20/2007	TM
IEEE Xplore (http://ieeexplore.ieee.org/Xplore/dynhome.jsp)	3/20/2007	TM
370/345.ccls. or 370/347.ccls. and (TDD or TDMA) and (synchronous or asynchronous)	3/20/2007	TM
Consulted with Rafael Perez-Gutierrez and George Bugg	3/20/2007	TM